

Abstract Submitted
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Magnetic Resonance Force Microscopy and Force-Detected NMR of Microcrystals¹ J. T. MARKERT, A. D. CAMBOU, J.-H. CHOI, S. GUCHHAIT, Y. J. LEE, W. LU, U. M. MIRSAIDOV, Department of Physics, University of Texas at Austin — We report our advances in nuclear magnetic resonance force microscopy (NMRFM) and NMR of microcrystals using force (mechanical oscillator) detection. For each, we report microfabrication of sensitive single-crystal-silicon multiple-torsional micro-oscillators using both optical and e-beam lithography and a back-etch technique. We characterize mechanical oscillator frequency, quality factor, and spring constant from the noise spectral density of oscillator motion, detected using fiber-optic interferometry. We review past work on scanning-mode detection of the NMR response from volumes as small as $2 \mu\text{m}^3$ at room temperature. We primarily discuss progress in two experiments currently underway: 1) the study of ^1H dynamics in submicron-thick metal hydride films, where the NMRFM technique permits selective response to motion-modulated dipolar interactions with correlation times from microseconds to seconds, and 2) detection of the ^{11}B resonance in microcrystals over the temperature range $4 \text{ K} < T < 300\text{K}$. We also overview measurements made in our ^3He low-temperature NMRFM system.

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